


<b>Search Notes</b>  	<b>Application/Control No.</b>  10815837	<b>Applicant(s)/Patent Under Reexamination</b>  KIM, NO-SOON
	<b>Examiner</b>  Chow, Yuk C	<b>Art Unit</b>  2609

SEARCHED			
Class	Subclass	Date	Examiner
345	77, 84, 102	4/27/2007	yc
348	362,222.1	4/27/2007	yc
250	338.1	10/4/2007	yc

SEARCH NOTES		
Search Notes	Date	Examiner
Updated East: most frequently detected = histogram	5/10/2008	yc
Update: Lee's histogram differs from claim 1, does not detect peak value, rather it calculates the average value	12/19/2008	yc

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
Same as above	See all of above	12/19/2008	yc

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